

Power effect of ZnO:Al film as back reflector on the performance of thin-film solar cells

Yang-Shih Lin, Shui-Yang Lien, Chao-Chun Wang, Chueh-Yang Liu, Asheesh

Nautiyal, Dong-Sing Wu, Pi-Chuen Tsai, Chia-Fu Chen and Shuo-Jen Lee

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SURFACES**Substrate grain size and orientation of Cu and Cu–Ni foils used for the growth of graphene films**

Zachary R. Robinson, Parul Tyagi, Thomas M. Murray, Carl A. Ventrice Jr., Shanshan

Chen, Andrew Munson, Carl W. Magnuson and Rodney S. Ruoff

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Sung Woo Yu, J. G. Tobin, Paul Olalde-Velasco, Wan Li Yang and Wigbert J. Siekhaus

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THIN FILMS**Probing compositional disorder in vanadium oxide thin films grown on atomic layer deposited hafnia on silicon by capacitance spectroscopy**

Changhyun Ko, You Zhou and Shriram Ramanathan

J. Vac. Sci. Technol. A **30**, 011501 (2012); <http://dx.doi.org/10.1116/1.3659020>[+ VIEW DESCRIPTION](#)**Deposition of novel nanocomposite films by a newly developed differential pumping co-sputtering system**

Masateru Nose, Takeshi Kurimoto, Atsushi Saiki, Kenji Matsuda and Kiyoshi Terayama

J. Vac. Sci. Technol. A **30**, 011502 (2012); <http://dx.doi.org/10.1116/1.3659704>[+ VIEW DESCRIPTION](#)**Compact tool for deposition of composition spread alloy films**

Deepika Priyadarshini, Petro Kondratyuk, James B. Miller and Andrew J. Gellman

J. Vac. Sci. Technol. A **30**, 011503 (2012); <http://dx.doi.org/10.1116/1.3664078>[+ VIEW DESCRIPTION](#)**Plasma etch characteristics of aluminum nitride mask layers grown by low-temperature plasma enhanced atomic layer deposition in SF₆ based plasmas**

Alexander Perros, Markus Bosund, Timo Sajavaara, Mikko Laitinen, Lauri Sainiemi, Teppo Huhtio and Harri Lipsanen

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Comparison of wet and dry etching of zinc indium oxide for thin film transistors with an inverted gate structure

Michael A. Marrs, Bryan D. Vogt and Gregory B. Raupp

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Transparent polycrystalline monoclinic HfO₂ dielectrics prepared by plasma assisted pulsed laser deposition

Zhifeng Ying, Jian Sun, Zhigao Hu, Wenlei Yu, Ning Xu and Jiada Wu

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VACUUM SCIENCE AND TECHNOLOGY**Effects of B₁₈H_x⁺ and B₁₈H_x dimer ion implantations on crystallinity and retained B dose in silicon**

Yoji Kawasaki and Kentaro Shibahara

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PERSPECTIVES**Thin-film electronics by atomic layer deposition**

David H. Levy and Shelby F. Nelson

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ATOMIC LAYER DEPOSITION (ALD)**Reaction mechanisms of atomic layer deposition of TaN_x from Ta(NMe₂)₅ precursor and H₂-based plasmas**

H. C. M. Knoop, E. Langereis, M. C. M. van de Sanden and W. M. M. Kessels

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Nucleation delay in atomic layer deposition on a thin organic layer and the role of reaction thermochemistry

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Scalability of plasma enhanced atomic layer deposited ruthenium films for interconnect applications

J. Swerts, S. Armini, L. Carbonell, A. Delabie, A. Franquet, S. Mertens, M. Popovici, M. Schaekers, T. Witters, Z. Tökei, G. Beyer, S. Van Elshocht, V. Gravey, A. Cockburn, K. Shah and J. Aubuchon

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ATOMIC LAYER DEPOSITION (ALD)

Charge trapping characteristics of Au nanocrystals embedded in remote plasma atomic layer-deposited Al₂O₃ film as the tunnel and blocking oxides for nonvolatile memory applications

Jaesang Lee, Hyungchul Kim, Taeyong Park, Youngbin Ko, Jaehun Ryu, Heeyoung Jeon, Jingyu Park and Hyeongtag Jeon

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Wetting properties induced in nano-composite POSS-MA polymer films by atomic layer deposited oxides

Kyle A. Vasquez, Anita J. Vincent-Johnson, W. Christopher Hughes, Brian H. Augustine, Kyoungmi Lee, Gregory N. Parsons and Giovanna Scarel

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Study of amorphous lithium silicate thin films grown by atomic layer deposition

Jani Hämäläinen, Frans Munnik, Timo Hatanpää, Jani Holopainen, Mikko Ritala and Markku Leskelä

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Combination of characterization techniques for atomic layer deposition MoO₃ coatings: From the amorphous to the orthorhombic α-MoO₃ crystalline phase

Madeleine Diskus, Ola Nilsen, Helmer Fjellvåg, Spyros Diplas, Pablo Beato, Clare Harvey, Evelien van Schroyen Lantman and Bert M. Weckhuysen

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Plasma and vacuum ultraviolet induced charging of SiO₂ and HfO₂ patterned structures

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Use of a high-flow diaphragm valve in the exhaust line of atomic layer deposition reactors

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Temperature induced changes in a AgPt nanofilm on Ru(0001)

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Thermal chemistry of Mn₂(CO)₁₀ during deposition of thin manganese films on silicon oxide and on copper surfaces

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Impact of electrode roughness on metal-insulator-metal tunnel diodes with atomic layer deposited Al₂O₃ tunnel barriers

Nasir Alimardani, E. William Cowell III, John F. Wager, John F. Conley Jr., David R.

Evans, Matthew Chin, Stephen J. Kilpatrick and Madan Dubey

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Thermal chemistry of copper(I)-N,N'-di-sec-butylacetamidinate on Cu(110) single-crystal surfaces

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Conformality of remote plasma-enhanced atomic layer deposition processes: An experimental study

Maarit Kariniemi, Jaakko Niinistö, Marko Vehkamäki, Marianna Kemell, Mikko

Ritala, Markku Leskelä and Matti Putkonen

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Core-shell nanowire arrays of metal oxides fabricated by atomic layer deposition

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Effect of pulsed deposition of Al₂O₃ for native oxides reduction of GaAs by atomic layer deposition technique

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Evaluation of high thermal stability cyclopentadienyl Hf precursors with H₂O as a co-reactant for advanced gate logic applications

Steven Consiglio, Robert D. Clark, Genji Nakamura, Cory S. Wajda and Gert J. Leusink

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Impact of precursor chemistry on atomic layer deposition of lutetium aluminates

Laura Nyns, Xiaoping Shi, Hilde Tielens, Sven Van Elshocht, Lucien Date and Robert Schreutelkamp

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Molecular layer deposition of polyethylene terephthalate thin films

Tatyana V. Ivanova, Philipp S. Maydannik and David C. Cameron

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Continuous atomic layer deposition: Explanation for anomalous growth rate effects

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Atomic layer deposition of Al₂O₃ on V₂O₅ xerogel film for enhanced lithium-ion intercalation stability

Dawei Liu, Yanyi Liu, Stephanie L. Candelaria, Guozhong Cao, Jun Liu and Yoon-Ha Jeong

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Al₂O₃ films and Al₂O₃/a-SiN_x:H stacks

W. Keuning, P. van de Weijer, H. Lifka, W. M. M. Kessels and M. Creatore

J. Vac. Sci. Technol. A **30**, 01A131 (2012); <http://dx.doi.org/10.1116/1.3664762>[+ VIEW DESCRIPTION](#)**Nanoscratch testing of atomic layer deposition and magnetron sputtered TiO₂ and Al₂O₃ coatings on polymeric substrates**

Tommi O. Kääriäinen, Peter J. Kelly, David C. Cameron, Ben Beake, Heqing Li, Paul M. Barker and Carolin F. Struller

J. Vac. Sci. Technol. A **30**, 01A132 (2012); <http://dx.doi.org/10.1116/1.3665418>[+ VIEW DESCRIPTION](#)**Real-time spectroscopic ellipsometric investigation of adsorption and desorption in atomic layer deposition: A case study for the strontium bis(tri-isopropylcyclopentadienyl)/water process**

Han Wang (王瀚), Xiaoqiang Jiang (蒋晓强) and Brian G. Willis

J. Vac. Sci. Technol. A **30**, 01A133 (2012); <http://dx.doi.org/10.1116/1.3664757>[+ VIEW DESCRIPTION](#)**Atomic layer deposition of titanium phosphate on silica nanoparticles**

Monika K. Wiedmann, David H. K. Jackson, Yomaira J. Pagan-Torres, Eunkyung Cho, James A. Dumesic and T. F. Kuech

J. Vac. Sci. Technol. A **30**, 01A134 (2012); <http://dx.doi.org/10.1116/1.3664097>[+ VIEW DESCRIPTION](#)**Growth characteristics, material properties, and optical properties of zinc oxysulfide films deposited by atomic layer deposition**

Jonathan R. Bakke, Jukka T. Tanskanen, Carl Hägglund, Tapani A. Pakkanen and Stacey F. Bent

J. Vac. Sci. Technol. A **30**, 01A135 (2012); <http://dx.doi.org/10.1116/1.3664758>[+ VIEW DESCRIPTION](#)**Evaluating operating conditions for continuous atmospheric atomic layer deposition using a multiple slit gas source head**

P. Ryan Fitzpatrick, Zachary M. Gibbs and Steven M. George

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J. Vac. Sci. Technol. A **30**, 01A137 (2012); <http://dx.doi.org/10.1116/1.3666026>[+ VIEW DESCRIPTION](#)**Atomic layer deposition of Al-doped ZnO films using ozone as the oxygen source: A comparison of two methods to deliver aluminum**

